

DUAL CHANNEL ILD620/620GB QUAD CHANNEL ILQ620/620GB AC INPUT PHOTOTRANSISTOR OPTOCOUPLER

FEATURES

- Identical Channel to Channel Footprint
ILD620 Crosses to TLP620-2
ILQ620 Crosses to TLP620-4
- Current Transfer Ratio (CTR) at $I_F = \pm 5$ mA
ILD/Q620: 50% Min.
ILD/Q620GB: 100% Min.
- Saturated Current Transfer Ratio (CTR_{SAT}) at $I_F = \pm 1$ mA
ILD/Q620: 60% Typ.
ILD/Q620GB: 30% Min.
- High Collector-Emitter Voltage, $BV_{CEO} = 70$ V
- Dual and Quad Packages Feature:
 - Reduced Board Space
 - Lower Pin and Parts Count
 - Better Channel to Channel CTR Match
 - Improved Common Mode Rejection
- Field-Effect Stable by TRIOS (TRansparent IO Shield)
- Isolation Test Voltage from Double Molded Package
- Underwriters Lab File #E52744
- VDE 0884 Available with Option 1

Maximum Ratings (Each Channel)

Emitter

Forward Current ± 60 mA
Surge Current ± 1.5 A
Power Dissipation 100 mW
Derate from 25°C 1.3 mW/°C

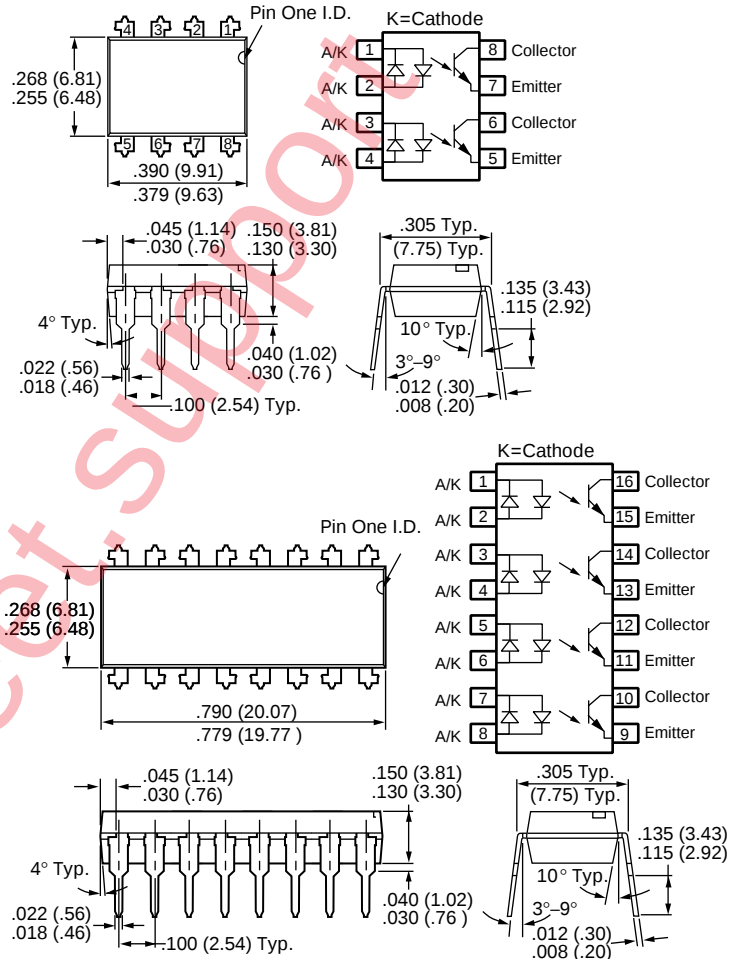
Detector

Collector-Emitter Breakdown Voltage 70 V
Collector Current 50 mA
Collector Current ($t < 1$ ms) 100 mA
Power Dissipation 150 mW
Derate from 25°C 2 mW/°C

Package

Isolation Test Voltage($t=1$ sec.) 5300 VAC_{RMS}
Package Dissipation, ILD620/GB 400 mW
Derate from 25°C 5.33 mW/°C
Package Dissipation, ILQ620/GB 500 mW
Derate from 25°C 6.67 mW/°C
Creepage 7 mm min.
Clearance 7 mm min.
Isolation Resistance
 $V_{IO}=500$ V, $T_A=25^\circ\text{C}$ $\geq 10^{12}$ Ω
 $V_{IO}=500$ V, $T_A=100^\circ\text{C}$ $\geq 10^{11}$ Ω
Storage Temperature -55°C to $+150^\circ\text{C}$
Operating Temperature -55°C to $+100^\circ\text{C}$
Junction Temperature 100°C
Soldering Temperature
(2 mm from case bottom) 260°C

Dimensions in inches (mm)



DESCRIPTION

The ILD/Q620 and ILD/Q620GB are multi-channel input phototransistor optocouplers that use inverse parallel GaAs IRLED emitters and high gain NPN silicon phototransistors per channel. These devices are constructed using over/under leadframe optical coupling and double molded insulation resulting in a Withstand Test Voltage of 7500 VAC_{PEAK}.

The LED parameters and the linear CTR characteristics combined with the TRIOS field-effect process make these devices well suited for AC voltage detection. The ILD/Q620GB with its low IF guaranteed CTR_{CESAT} minimizes power dissipation of the AC voltage detection network that is placed in series with the LEDs. Eliminating the phototransistor base connection provides added electrical noise immunity from the transients found in many industrial control environments.

Characteristics

	Symbol	Min.	Typ.	Max.	Unit	Condition
Emitter						
Forward Voltage	V_F	1	1.15	1.3	V	$I_F = \pm 10$ mA
Forward Current	I_F		2.5	20	μ A	$V_R = \pm 0.7$ V
Capacitance	C_O		25		pF	$V_F = 0$ V, $f = 1$ MHz
Thermal Resistance, Junction to Lead	R_{THJL}		750		$^{\circ}$ C/W	
Detector						
Capacitance	C_{CE}		6.8		pF	$V_{CE} = 5$ V, $f = 1$ MHz
Collector-Emitter Leakage Current	I_{CEO}		10	100	nA	$V_{CE} = 24$ V
Collector-Emitter Leakage Current	I_{CEO}		2	50	μ A	$T_A = 85^{\circ}$ C, $V_{CE} = 24$ V
Thermal Resistance, Junction to Lead	R_{THJL}		500		$^{\circ}$ C/W	
Package Transfer Characteristics						
Channel/Channel CTR Match	CTRX/CTRY	1 to 1		3 to 1		$I_F = \pm 5$ mA, $V_{CE} = 5$ V
CTR Symmetry	$I_{CE(RATIO)}$	0.5		2		$I_{CE}(I_F = -5$ mA)/ $I_{CE}(I_F = +5$ mA)
Off-State Collector Current	$I_{CE(OFF)}$		1	10	μ A	$V_F = \pm 0.7$ V, $V_{CE} = 24$ V
ILD/Q620						
Saturated Current Transfer Ratio	CTR_{CESat}		60		%	$I_F = \pm 1$ mA, $V_{CE} = 0.4$ V
Current Transfer Ratio	CTR_{CE}	50	80	600	%	$I_F = \pm 5$ mA, $V_{CE} = 5$ V
Collector-Emitter Saturation Voltage	V_{CESat}			0.4	V	$I_F = \pm 8$ mA, $I_{CE} = 2.4$ mA
ILD/Q620GB						
Saturated Current Transfer Ratio	CTR_{CESat}	30			%	$I_F = \pm 1$ mA, $V_{CE} = 0.4$ V
Current Transfer Ratio (Collector-Emitter)	CTR_{CE}	100	200	600	%	$I_F = \pm 5$ mA, $V_{CE} = 5$ V
Collector-Emitter Saturation Voltage	V_{CESat}			0.4	V	$I_F = \pm 1$ mA, $I_{CE} = 0.2$ mA
Isolation and Insulation						
Common Mode Rejection, Output High	CMH		5000		V/ μ s	$V_{CM} = 50$ V _{P-P} , $R_L = 1$ k Ω , $I_F = 0$ mA
Common Mode Rejection, Output Low	CML		5000		V/ μ s	$V_{CM} = 50$ V _{P-P} , $R_L = 1$ k Ω , $I_F = 10$ mA
Common Mode Coupling Capacitance	C_{CM}		0.01		pF	
Package Capacitance	CI-O	0.8			pF	$V_{I-O} = 0$ V, $f = 1$ MHz
Insulation Resistance	R_S		10^{12}		Ω	$V_{I-O} = 500$ V
Channel to Channel Insulation		500			VAC	

Switching Times

Figure 1. Non-saturated switching timing

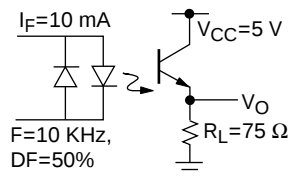


Figure 2. Saturated switching timing

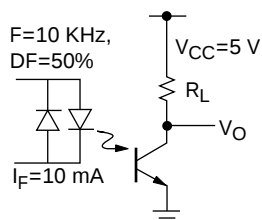


Figure 3. Non-saturated switching timing

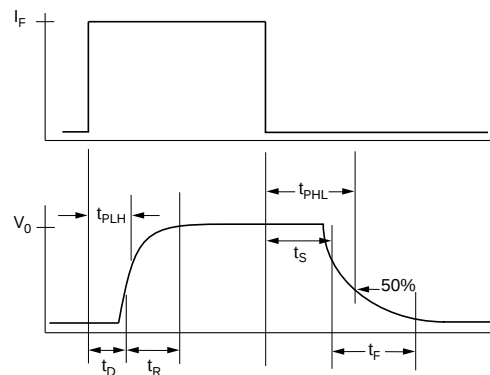
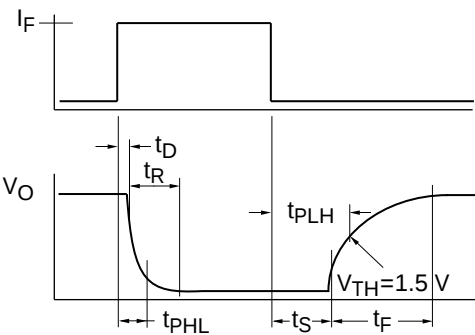


Figure 4. Saturated switching timing



Characteristic	Symbol	Typ.	Unit	Test Condition
On Time	T _{ON}	3.0	μs	I _F =±10 mA V _{CC} =5 V R _L =75 Ω 50% of V _{PP}
Rise Time	t _R	20	μs	
Off Time	t _{OFF}	2.3	μs	
Fall Time	t _F	2.0	μs	
Propagation H-L	t _{PHL}	1.1	μs	
Propagation L-H	t _{PLH}	2.5	μs	

Characteristic	Symbol	Typ.	Unit	Test Condition
On Time	T _{ON}	4.3	μs	I _F =±10 mA V _{CC} =5 V R _L =1 Ω V _{TH} =1.5 V
Rise Time	t _R	2.8	μs	
Off Time	t _{OFF}	2.5	μs	
Fall Time	t _F	11	μs	
Propagation H-L	t _{PHL}	2.6	μs	
Propagation L-H	t _{PLH}	7.2	μs	

Figure 5. LED forward current versus forward voltage

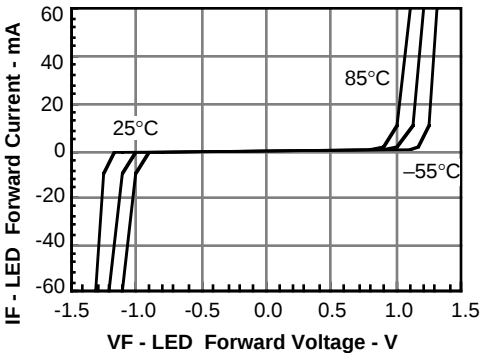


Figure 6. Collector-emitter leakage versus temperature

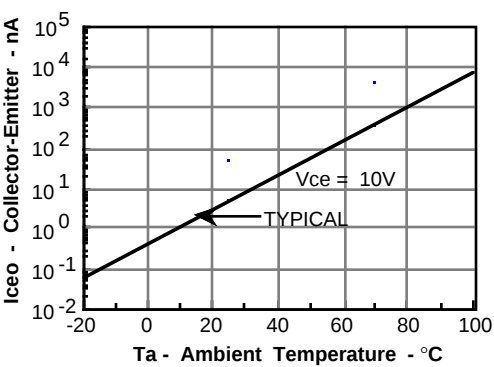


Figure 7. Maximum LED current versus ambient temperature

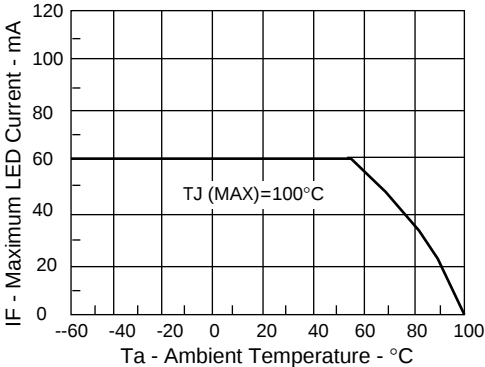


Figure 8. Maximum LED power dissipation

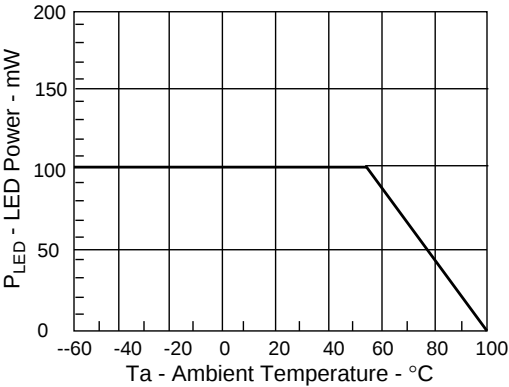


Figure 9. Collector current versus diode forward current

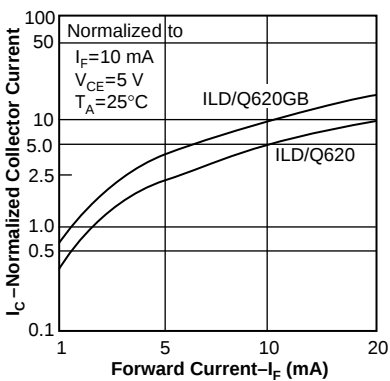


Figure 10. Normalization factor for non-saturated and saturated CTR $T_A=50^{\circ}\text{C}$ versus I_F

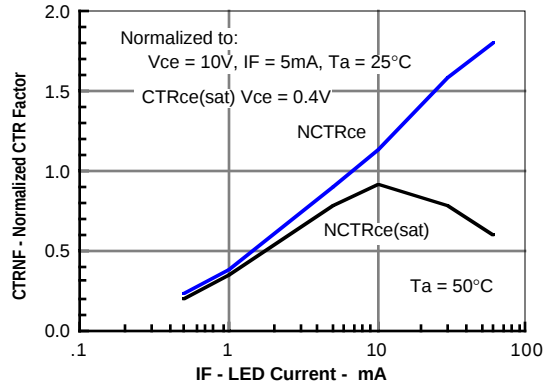


Figure 11. Normalization factor for non-saturated and saturated CTR $T_A=70^{\circ}\text{C}$ versus I_F

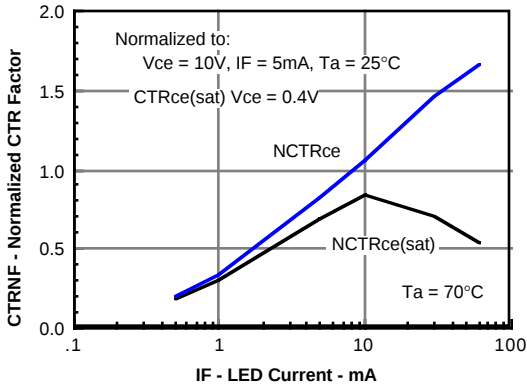


Figure 12. Normalization factor for non-saturated and saturated CTR $T_A=100^{\circ}\text{C}$ versus I_F

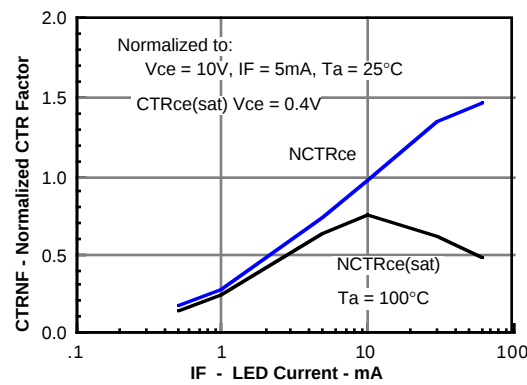


Figure 13. Peak LED current versus peak duration, τ

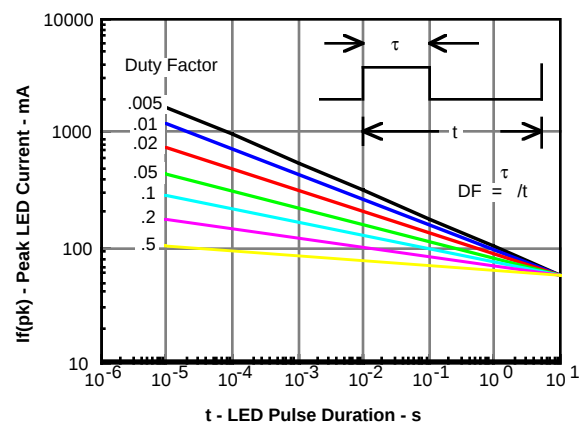


Figure 14. Maximum detector power dissipation

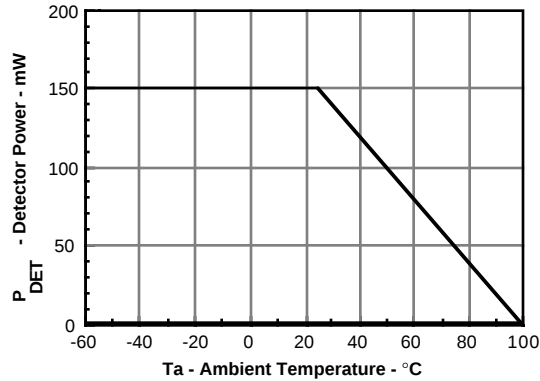


Figure 15. Maximum collector current versus collector voltage

